

## Qualification Results Summary for ADE7932/ADE7933 Die Revision

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)* <sup>2</sup>	JEDEC <i>JESD22-A108</i>	<b>9 x 77</b>	<b>Pass</b>
Highly Accelerated Stress Test (HAST)* <sup>1</sup>	JEDEC <i>JESD22-A110</i>	<b>9 x 77</b>	<b>Pass</b>
Temperature Cycle (TC)* <sup>1</sup>	JEDEC <i>JESD22-A104</i>	<b>9 x 77</b>	<b>Pass</b>
Unbiased HAST* <sup>1</sup>	JEDEC <i>JESD22-A118</i>	<b>9 x 77</b>	<b>Pass</b>
High Temperature Storage Life (HTSL) <sup>1</sup>	JEDEC <i>JESD22-A103</i>	<b>9 x 77</b>	<b>Pass</b>
Solder Heat Resistance (SHR)* <sup>1</sup>	JEDEC/IPC <i>J-STD-020</i>	<b>1 x 30</b>	<b>Pass</b>
Latch-Up <sup>1</sup>	JEDEC <i>JESD78</i>	<b>1 x 18</b>	<b>Pass ±200mA @ +5.445V</b>
Electrostatic Discharge <i>Human Body Model</i> <sup>1</sup>	ESDA/JEDEC <i>JS-001</i>	<b>3/voltage</b>	<b>Pass ±1000V</b>
Electrostatic Discharge <i>Field-Induced Charged Device Model</i> <sup>1</sup>	JEDEC <i>JS-002</i>	<b>3/voltage</b>	<b>Pass ±1250V</b>

\*Preconditioned per JEDEC/IPC J-STD-020

<sup>1</sup>Electrical test was performed at Room